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## Short communication

# Mechanical and dielectric properties of porous Si<sub>3</sub>N<sub>4</sub> ceramics using PMMA as pore former

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### **Abstract**

Porous  $Si_3N_4$  ceramics were prepared using PMMA as pore former, and the mechanical and dielectric properties were investigated, as a function of porosity. Higher porosity was achieved at lower sintering temperature with lower sintering additive and more PMMA. The flexural strength decreased exponentially with increasing the porosity and the pore size. The dielectric constant decreased with increasing the porosity and the frequency has less effect on the dielectric constant.

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#### 1. Introduction

Silicon nitride  $(Si_3N_4)$  ceramics usually is described as an ideal engineering material because of its superior properties, such as the high-decomposition temperature, the high strength at room and elevated temperatures, low coefficient of friction and resistance to environments [1,2], as well as the excellent oxidation and thermal shock resistance [3–9]. Moreover, silicon nitride also has good dielectric properties and it attracts much attention [10,11]. But for practical applications, it is very important to develop  $Si_3N_4$  with low dielectric constant  $(\epsilon)$  and low dielectric loss (tan  $\delta$ ) since the dielectric absorption of microwave power leads to inhomogeneous temperature profiles and can damage the quality of the products [12].

Pore design is considered as an effective way to decrease dielectric constant. It is well known that the dielectric constant is mainly dependent on porosity in porous ceramics [13–15]. Furthermore, dielectric constant is also affected by pore morphology. Spherical pores exhibit higher piezoelectric coefficient and remnant polarization compared with irregular pores [16]. Polymethyl methacrylate (PMMA) is a kind of spherical particles and can be easily burned out. Compared with

other preparation method of porous  $Si_3N_4$  ceramics, e.g., carbothermal nitridation [17]; combustion synthesis [18]; *in situ* reaction bonding [19]; freeze casting [20], the porosity and the pore size can be easily controlled by adjusting the content and the size of adding PMMA. So it is a good way to prepare porous  $Si_3N_4$  ceramics with low dielectric constant by adding PMMA as pore former.

In this paper, porous  $\mathrm{Si_3N_4}$  ceramics with controlled porosity were fabricated by liquid phase sintering. The phase composition, microstructure, mechanical and dielectric properties as a function of porosity were investigated. To keep the  $\alpha$ : $\beta$ - $\mathrm{Si_3N_4}$  ratio and the content of liquid phase, samples sintered at 1800 °C with 5% additives were chosen to study the influence of porosity on flexural strength and dielectric constant.

## 2. Experimental procedure

 $\alpha\text{-Si}_3N_4$  (SN-E10, purity  $>99.5\%,\,\alpha$  ratio  $>95\%,\,$  average particle size of 0.5  $\mu\text{m};\,$  UBE Industries, Ltd., Tokyo, Japan),  $Y_2O_3$  (purity  $\geq 99.99$  wt%; Yuelong company, Shanghai, China, average particle size of 3  $\mu\text{m})$  and  $Al_2O_3$  (purity  $>99.9\%,\,\,\alpha$  ratio  $>95\%,\,\,$  average particle size of 0.5  $\mu\text{m};\,\,$  Wusong Fertilizer Factory, Shanghai, China) were used as the starting materials.  $Al_2O_3$ :Y $_2O_3$  in the fixed mole ratio of 2.98:1 were used as sintering additives with the content of 3, 5, 10 wt%. Polymethyl methacrylate (PMMA, Shanghai

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Coral Factory, Shanghai, China) with the particle size of 425–  $250 \mu m$ ,  $150-250 \mu m$  and  $150-74 \mu m$  were used as pore formers. A mixture of α-Si<sub>3</sub>N<sub>4</sub>, Al<sub>2</sub>O<sub>3</sub>, Y<sub>2</sub>O<sub>3</sub> and PMMA was ball-milled in ethanol for 24 h. After dried and sieved through a screen, the powder was pressed into rectangular bars with dimensions of  $5.0 \times 6.0 \times 45.0$  mm at 100 MPa. The bars were firstly heated at 600 °C in air with a heating rate of 2 °C/min for 3 h to burn out the PMMA and then sintered at 1700-1850 °C in 0.5 MPa nitrogen atmosphere for 2 h at a heating and cooling rates of 5 °C/min. Samples were machined into a rectangle bar with dimension of  $3.0 \times 4.0 \times 36.0 \,\mathrm{mm}$  to measure the flexural strength via the three point bending test (Model AUTOGRAPH AG-I, Shimadzu, Japan), the support distance of 30 mm and a cross-head speed of 0.5 mm/min were used. The porosity and bulk density were determined by the Archimedes method using distilled water as medium. Phase analysis was conducted by X-ray diffraction (XRD) (Model RAX-10, Rigaku, Japan) with Cu Kα radiation (wavelength of 1.5418 Å). Morphology of porous Si<sub>3</sub>N<sub>4</sub> ceramics was observed by scanning electron microscopy (SEM) (Model JXA-8100, JEOL, Tokyo, Japan). The dielectric constant and dielectric loss of the samples with the size  $\Phi$ 3.00  $\times$  30.00 mm were measured in the frequency range of 1.96-12.1 GHz at room temperature by RF impedance/ material analyzer (Model E8363A, Agilent, USA). The pore size distribution was determined by mercury porosimetry (Model pore sizer 9320, Micrometritics Co. Ltd., USA).

## 3. Results and discussion

Fig. 1 shows the XRD pattern of porous  $Si_3N_4$  ceramics prepared at different sintering temperature. It can be seen that the phase transformation from  $\alpha$ - $Si_3N_4$  to  $\beta$ - $Si_3N_4$  is completely accomplished. In addition, an obvious peak of  $Y_2Si_3O_3N_4$  was found [21]. This can be explained that added  $Y_2O_3$  reacts with the  $SiO_2$ – $Si_3N_4$  [22]. The  $SiO_2$  is from the surface of  $Si_3N_4$  particle.

Fig. 2 shows the microstructure of porous  $Si_3N_4$  ceramics. It can be seen that the  $\beta$ - $Si_3N_4$  grains are fine with little additive; and it grows up with more additive. Solution-reprecipitation, which is controlled by the diffusion of Si and N ions through the boundary phase, is thought the main growth mechanism of  $\beta$ -

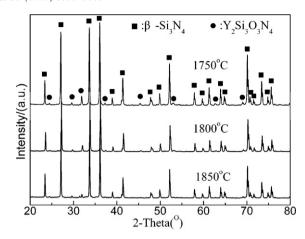


Fig. 1. XRD pattern of porous Si<sub>3</sub>N<sub>4</sub> ceramics at different sintering temperature.

 $Si_3N_4$  in liquid phase [23]. So the content of liquid phase influences the morphology of  $\beta$ - $Si_3N_4$  grains.

Fig. 3 shows the pores microstructure of decomposing PMMA. In the case of samples containing 300  $\mu m$  PMMA, only a small quantity of pores is visible. And more spherical pores are observed in Fig. 3(b) because more small size PMMA is added. Some pore shape deforms because the thin wall of pore slumps owing to liquid-phase sintering in high temperature when large size PMMA is burned out. In sintering process, the pore is deformed owing to shrinkage. With pore size increasing, the deformation area of pore increase. And the deformation result in pore slumps. So the porosity and pore size can be controlled by adding pore formers.

Fig. 4 shows the flexural strength of porous  $Si_3N_4$  ceramics. It is considered that porosity, pore size, intrinsic strength of the materials (grain and grain boundary) and microstructure are typical four determining factors for the strength of porous ceramics [24]. Regarding to the samples with different PMMA content, porosity and microstructure are the main influencing factors for the strength. It is well known that the strength decreases exponentially with increasing the porosity. Normally, more additives result in lower porosity. Furthermore, the microstructure also affects the strength. The fibrous  $\beta$ -Si<sub>3</sub>N<sub>4</sub> grains, as whiskers, are helpful to the strength of ceramics. Typically, specimens with longer  $\beta$ -Si<sub>3</sub>N<sub>4</sub> grains have higher strength with the same porosity [24].

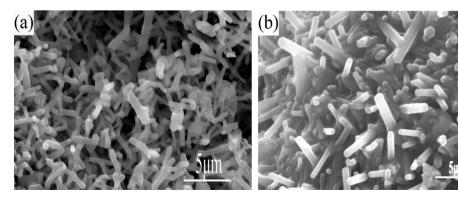


Fig. 2. The microstructure of porous  $Si_3N_4$  ceramics: (a) 3 wt%  $(Y_2O_3 + Al_2O_3)$ –10% PMMA (74  $\mu$ m) at 1800 °C; (b) 10 wt%  $(Y_2O_3 + Al_2O_3)$ –10% PMMA (74  $\mu$ m) at 1800 °C.

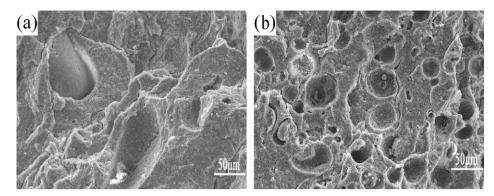


Fig. 3. The microstructure of porous  $Si_3N_4$  ceramics: (a) 5% ( $Y_2O_3 + Al_2O_3$ )-30% PMMA ( $300~\mu m$ ) at  $1800~^{\circ}C$ ; (b) 5% ( $Y_2O_3 + Al_2O_3$ )-30% PMMA ( $74~\mu m$ ) at  $1800~^{\circ}C$ .

As shown in Fig. 5, with increasing the content of PMMA, the porosity of ceramics increases and the flexural strength decreases. The relation between flexural strength ( $\sigma$ ) and porosity (P) can be expressed as following equation [25,26]:

$$\sigma = \sigma_0 \exp(-\beta P) \tag{1}$$

where  $\sigma_0$  is the flexural strength at a porosity of 0 and  $\beta$  is the structural factor. It can be seen from Fig. 6 that flexural strength and porosity of porous  $Si_3N_4$  ceramics approximately fit the Eq. (1). But there are two data deviating from the line in Fig. 6. One is lower than normal value because the pore size is larger, and the other one is higher than normal value because the pore size is smaller. It can be seen from Fig. 3 that the size of residual pore is similar to the size of adding PMMA.

Fig. 7 shows the relationship between the dielectric constant ( $\varepsilon$ ) of samples and the frequency. It can be seen that the dielectric constant is less dependent on the frequency. As the frequency increases, the dielectric constants almost keep the same. Samples with different dielectric constant are mainly due to the gradual introduction of air filled pores in the matrix, which increases the porosity and affects dielectric constant. If the pores are spherical and considered as a second phase, the

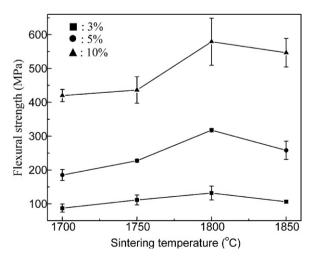


Fig. 4. The flexural strength of porous  $Si_3N_4$  ceramics sintered at different temperature with different content additives.

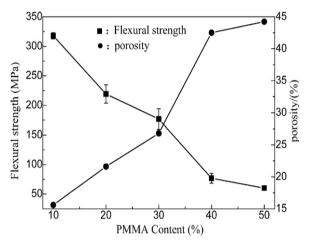


Fig. 5. The flexural strength and porosity of porous  $Si_3N_4$  ceramics sintered with different content PMMA.

dielectric constant can be expressed as following equation [27]:

$$\varepsilon' = \varepsilon_m \left[ 1 - \frac{3P(\varepsilon_m - 1)}{2\varepsilon_m + 1 - P + P\varepsilon_m} \right] \tag{2}$$

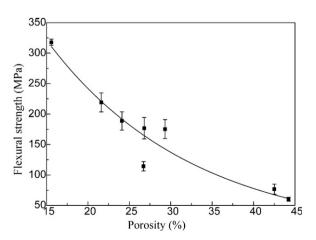


Fig. 6. The relationship between flexural strength and porosity with 5%  $(Y_2O_3 + Al_2O_3)$  at 1800 °C.

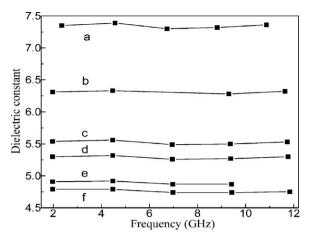


Fig. 7. The dielectric constant of porous  $Si_3N_4$  ceramics: (a) 10% ( $Y_2O_3+Al_2O_3$ )–10% PMMA at 1800 °C, (b) 5% ( $Y_2O_3+Al_2O_3$ )–10% PMMA at 1800 °C, (c) 5% ( $Y_2O_3+Al_2O_3$ )–30% PMMA (150  $\mu$ m) at 1800 °C, (d) 5% ( $Y_2O_3+Al_2O_3$ )–30% PMMA (300  $\mu$ m) at 1800 °C, (e) 5% ( $Y_2O_3+Al_2O_3$ )–30% PMMA (74  $\mu$ m) at 1800 °C, (f) 3% ( $Y_2O_3+Al_2O_3$ )–10% PMMA at 1800 °C.

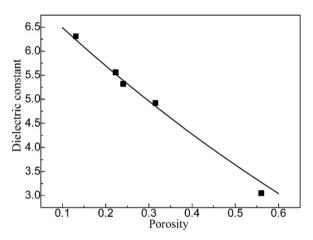


Fig. 8. The relationship between dielectric constant and porosity with 5% ( $Y_2O_3 + Al_2O_3$ ) at 1800 °C.

where  $\varepsilon'$  and  $\varepsilon_m$  is the dielectric constant of porous and fully dense materials, respectively, and P is the porosity. It can be seen from Fig. 8 that this is a good fit to the data. And it proved that the dielectric constant of porous Si<sub>3</sub>N<sub>4</sub> ceramics decreases with porosity.

### 4. Conclusions

Porous  $Si_3N_4$  ceramics with controlled porosity were prepared by adding PMMA as pore-forming agent. The porosity and pore size were successfully controlled by the sintering temperature, sintering additives and adding PMMA. The porous ceramics had high porosity with fine  $\beta$ - $Si_3N_4$  grains at low sintering additive. The flexural strength decreased exponentially with increasing the porosity and increased with smaller pore size. The dielectric constant is mainly dependent on the porosity, but less dependent on the frequency.

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#### References

- [1] E.J. Opila, R.C. Robinson, D.S. Fox, R.A. Wenglarz, M.K. Ferber, Additive effects on  $Si_3N_4$  oxidation/volatilization in water vapor, J. Am. Ceram. Soc. 86 (2003) 1262–1271.
- [2] H. Rho, N.L. Hecht, G.A. Graves, Oxidation behavior of hot isostatically pressed silicon nitride containing Y<sub>2</sub>O<sub>3</sub>, J. Mater. Sci. 35 (2000) 3631– 3639
- [3] N.N. Ault, R. Yeckley, silicon nitride, Am. Ceram. Soc. Bull. 74 (1995) 153–155.
- [4] M.A. Einarsrud, M. Mitomo, Mechanism of grain growth of β-SiAlON, J. Am. Ceram. Soc. 76 (1993) 1624–1626.
- [5] O. Abe, Sintering process of  $Y_2O_3$  and  $Al_2O_3$ -doped  $Si_3N_4$ , J. Mater. Sci. 25 (1990) 4018–4026.
- [6] J.C. Almeida, A.T. Fonseca, R.N. Correia, J.L. Baptista, Pressureless sintering of silicon nitride with additives of the Y<sub>2</sub>O<sub>3</sub>–Al<sub>2</sub>O<sub>3</sub>–SiO<sub>2</sub> system, Mater. Sci. Eng. A 109 (1989) 395–400.
- [7] N. Hirosaki, A. Okada, K. Matoba, Sintering of  $Si_3N_4$  with the addition of rare-earth oxides, J. Am. Ceram. Soc. 71 (1988) 144–147.
- [8] B. Matovic, G. Rixecker, F. Aldinger, Densification of Si<sub>3</sub>N<sub>4</sub> with LiYO<sub>2</sub> additive, J. Am. Ceram. Soc. 87 (2004) 546–549.
- [9] J.F. Yang, T. Ohji, K. Niihara, Influence of yttria–alumina content on sintering behavior and microstructure of silicon nitride ceramics, J. Am. Ceram. Soc. 83 (2000) 2094–2096.
- [10] T. Goto, T. Hirai, Dielectric properties of chemically vapour-deposited Si<sub>3</sub>N<sub>4</sub>, J. Mater. Sci. 24 (1989) 821–826.
- [11] J.Q. Li, F. a Luo, D.M. Zhu, W.C. Zhou, Influence of phase formation on dielectric properties of Si<sub>3</sub>N<sub>4</sub>, J. Am. Ceram. Soc. 90 (2007) 1950–1952.
- [12] H. Miyazaki, Y.I. Yoshizawa, K. Hirao, Effect of crystallization of intergranular glassy phases on the dielectric properties of silicon nitride ceramics, Mater. Sci. Eng. B 148 (2008) 257–260.
- [13] J. Xu, F. Luo, D. Zhu, X. Su, W. Zhou, Effect of presintering on the dielectric and mechanical properties of porous reaction-bonded silicon nitride, Mater. Sci. Eng. A 488 (2008) 167–171.
- [14] X. Li, X. Yin, L. Zhang, L. Cheng, Y. Qi, Mechanical and dielectric properties of porous Si<sub>3</sub>N<sub>4</sub>–SiO<sub>2</sub> composite ceramics, Mater. Sci. Eng. A 500 (2009) 63–69.
- [15] S. Penn, N. Alford, A. Templeton, X. Wang, M. Xu, M. Reece, K. Schrapel, Effect of porosity and grain size on the microwave dielectric properties of sintered alumina, J. Am. Ceram. Soc. 80 (1997) 1885–1888.
- [16] T. Zeng, X. Dong, C. Mao, Z. Zhou, H. Yang, Effects of pore shape and porosity on the properties of porous PZT 95/5 ceramics, J. Eur. Ceram. Soc. 27 (2007) 2025–2029.
- [17] S.Y. Shan, J.F. Yang, J.Q. Gao, W.H. Zhang, Z.H. Jin, Porous silicon nitride ceramics prepared by reduction-nitridation of silica, J. Am. Ceram. Soc. 88 (2005) 2594–2596.
- [18] D. Chen, B. Zhang, H. Zhuang, W. Li, Combustion synthesis of network silicon nitride porous ceramics, Ceram. Int. 29 (2003) 263–264.
- [19] S. Ding, Y.P. Zeng, D. Jiang, Oxidation bonding of porous silicon nitride ceramics with high strength and low dielectric constant, Mater. Lett. 61 (2007) 1180–2277.
- [20] T. Fukasawa, Z.Y. Deng, M. Ando, T. Ohji, S. Kanzaki, Synthesis of porous silicon nitride with unidirectionally aligned channels using freezedrying process, J. Am. Ceram. Soc. 85 (2002) 2151–2155.
- [21] S. Chockalingam, D.A. Earl, V.R.W. Amarakoon, Phase transformation and densification behavior of microwave-sintered Si<sub>3</sub>N<sub>4</sub>-Y<sub>2</sub>O<sub>3</sub>-MgO-ZrO<sub>2</sub> system, Int. J. Appl. Ceram. Technol. 6 (2009) 102–110.
- [22] T. Honma, Y. Ukyo, Sintering process of Si<sub>3</sub>N<sub>4</sub> with Y<sub>2</sub>O<sub>3</sub> and Al<sub>2</sub>O<sub>3</sub> as sintering additives, J. Mater. Sci. Lett. 18 (1999) 735–737.

- [23] A. Verma, P. Krishna, Polymorphism and Polytypism in Crystals, John Wiley and Sons, New York, 1951.
- [24] C. Kawai, Effect of grain size distribution on the strength of porous  $Si_3N_4$  ceramics composed of elongated  $\beta$ -Si $_3N_4$  grains, J. Mater. Sci. 36 (2001) 5713–5717.
- [25] R.L. Coble, W.D. Kingery, Effect of porosity on physical properties of sintered alumina, J. Am. Ceram. Soc. 39 (1956) 377–385.
- [26] R.M. Spriggs, Expression for effect of porosity on elastic modulus of polycrystalline refractory materials, particularly aluminum oxide, J. Am. Ceram. Soc. 44 (1961) 628–629.
- [27] S.J. Penn, N.M. Alford, A. Templeton, X. Wang, M. Xu, M. Reece, K. Schrapel, Effect of porosity and grain size on the microwave dielectric properties of sintered alumina, J. Am. Ceram. Soc. 80 (1997) 1885–1888.